Attorney's Docket No.: 14925-010001/FP03-0355-00US-SE

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Takao Nakamura et al.

Serial No.: Unknown

Filed : March 23, 2004

Title : SEMICONDUCTOR OPTICAL DEVICE, METHOD OF FORMING

CONTACT IN SEMICONDUCTOR OPTICAL DEVICE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants call attention to the attached Information
Disclosure Statement and documents listed on form PTO-1449.

This filing is being made before the receipt of a first Office action on the merits. No fee is required.

Consideration of the foregoing and enclosures plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

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Respectfully submitted,

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Substitute Form PTO-1449 Modified) U.S. Department of Commerce Patent and Trademark Office				
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Takao Nakamura et al.		
		Filing Date March 23, 2004	Group Art Unit Unknown	

			U.S. Pat	ent Documents			
Examiner Initial	Desig. ID	Document Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,396,103	03/07/1995	Oiu et al.			
	AB	5,548,137	08/20/1996	Fan et al.			
	AC						
	AD						
	AE						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Translation	
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
							X	
	AF 06-310815	06-310815	11/04/1994	Japan			(Abstract	
						Only)		
							X	
AG 06-005920	06-005920	01/14/1994	Japan			(Abstract		
						Only)		
	AH							

Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner	Desig.			
Initial	ID ID	Document		
	AI	Takao Nakamura et al., Optronics (2000) No. 12, pp.126-131 (partial translation)		
	AJ	Y. Fan et al., "Graded band gap ohmic contact to <i>p-Z</i> nSe", <u>Appl. Phys. Lett.</u> , 61 (26), 12/28/1992, pp. 3160-3162		
	AK			

Examiner Signature			Date Considered		_
		 	<u> </u>	 	

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.